

650V GaN HEMT

Description

The CC65H160DNGI Series 650V, 160mΩ gallium nitride (GaN) FETs are normally-off devices.

Classicchip GaN FETs offer better efficiency through lower gate charge, faster switching speeds, and lower dynamic on resistance, delivering significant advantages over traditional silicon (Si) devices.

Classicchip is a leading-edge wide band gap supplier with world-class innovation .

Automotive

-  Adapter
-  Renewable energy
-  Telecom and data-com
-  Servo motors
-  Industrial
-  Automotive

General Features

Easy to drive —compatible with standard gate drivers

Low conduction and switching losses

RoHS compliant and Halogen-free

Benefits

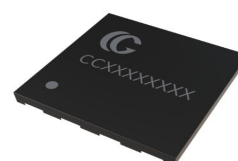
Increased efficiency through fast switching

Increased power density

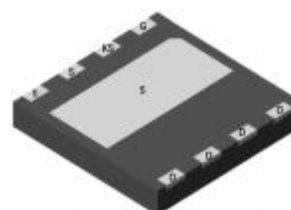
Reduced system size and weight

Ordering Information

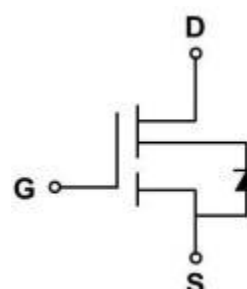
Part Number	Package	Package Configuration
CC65H160DNGI	DFN 8*8	Source



Top



Bottom



Circuit Symbol

Features

BV_{DSS}	$R_{DS(on)}$	I_{DS}	Q_G
650V	160mΩ	16A	7.8nC

Absolute Maximum Ratings

$T_C=25$. °C unless otherwise stated

Symbol	Parameter		Limit value	Unit
V_{DSS}	Drain to source voltage ($T_J = -55$. °C to 150 . °C)		650	V
$V_{(TR)DSS}$	Drain to source voltage-transient ^a		800	
V_{GSS}	Gate to source voltage		-20~+20	
I_D	Continuous drain current @ $T_C=25$. °C ^b		16	A
	Continuous drain current @ $T_C=125$. °C ^b		7	
I_{DM}	Pulse drain current (pulse width: 100µs)		23	A
P_D	Maximum power dissipation @ $T_C=25$. °C		78	W
T_C	Operating temperature	Case	-55~150	°C
T_J		Junction	-55~150	°C
T_S		Storage temperature	-55~150	°C

a. In off-state, spike duty cycle $D<0.01$, spike duration $<1\mu s$

b. For increased stability at high current operation

Thermal Resistance

Symbol	Parameter	Limit value	Unit
$R_{\theta JC}$	Junction -to - case	1.6	° C /W

Electrical Parameters

$T_J=25.^\circ\text{C}$ unless otherwise stated

Symbol	Parameter	Min	Typ	Max	Unit	Test Conditions
Forward Device Characteristics						
$V_{(BL)DSS}$	Drain-source voltage	650	-	-	V	$V_{GS}=0V$
$V_{GS(th)}$	Gate threshold voltage	-	1.7	-	V	
$\Delta V_{GS(th)}/T_J$	Gate threshold voltage temperature coefficient	-	-6.8	-	mV/ $^\circ\text{C}$	$V_{DS}=1V, I_{DS}=1mA$
$R_{DS(on)}$	Drain-source on-resistance	-	160	190	m Ω	$V_{GS}=10V, I_D=1A, T_J=25.^\circ\text{C}$
		-	340	-		$V_{GS}=10V, I_D=1A, T_J=150.^\circ\text{C}$
I_{DSS}	Drain-to-source leakage current	-	-	10	μA	$V_{DS}=650V, V_{GS}=0V, T_J=25.^\circ\text{C}$
		-	-	100		$V_{DS}=650V, V_{GS}=0V, T_J=150.^\circ\text{C}$
I_{GSS}	Gate-to-source forward leakage current	-	-	± 100	nA	$V_{GS}=\pm 20V$
C_{ISS}	Input capacitance	-	378	-	pF	$V_{GS}=0V, V_{DS}=400V, f=1MHz$
C_{OSS}	Output capacitance	-	23	-		
C_{RSS}	Reverse capacitance	-	0.97	-		
Q_G	Total gate charge	-	7.8	-	nC	$V_{DS}=400V, V_{GS}=0V \text{ to } 10V, I_D=1A$
Q_{GS}	Gate-source charge	-	1.1	-		
Q_{GD}	Gate-drain charge	-	1.8	-		
Q_{OSS}	Output charge	-	36	-	nC	$V_{GS}=0V, V_{DS}=0V \text{ to } 400V, f=1MHz$
$t_{D(on)}$	Turn-on delay	-	2.5	-	ns	$V_{DS}=400V, V_{GS}=0V \text{ to } 10V, I_D=2.1A,$ $R_{G-on(ext)}=6.8\Omega, R_{G-off(ext)}=2.2\Omega,$ $L=250\mu H$
t_R	Rise time	-	7	-		
$t_{D(off)}$	Turn-off delay	-	9.7	-		
t_F	Fall time	-	28	-		

Electrical Parameters

$T_J=25$. °C unless otherwise stated

Symbol	Parameter	Min	Typ	Max	Unit	Test Conditions
Reverse Device Characteristics						
V_{SD}	Source- Drain reverse voltage	-	2.5	-	V	$V_{GS}=0V$, $I_{SD}=10A$
t_{RB}	Reverse recovery time	-	13	-	ns	$I_F=10A$, $V_{DD}=400V$, $dI_F/dt=165A/\mu s$
Q_{RR}	Reverse recovery charge	-	3.2	-	nC	

Typical Characteristics

$T_J=25$. °C unless otherwise stated

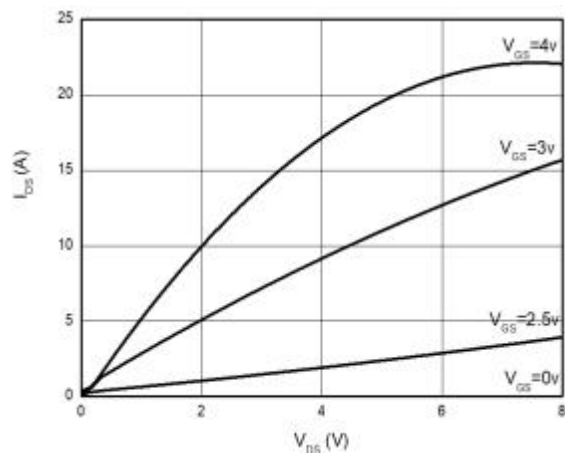


Figure 1. Typical Output Characteristics $T_J=25$. °C

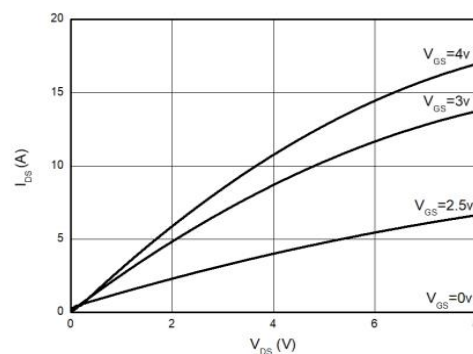


Figure 2. Typical Output Characteristics $T_J=125$. °C

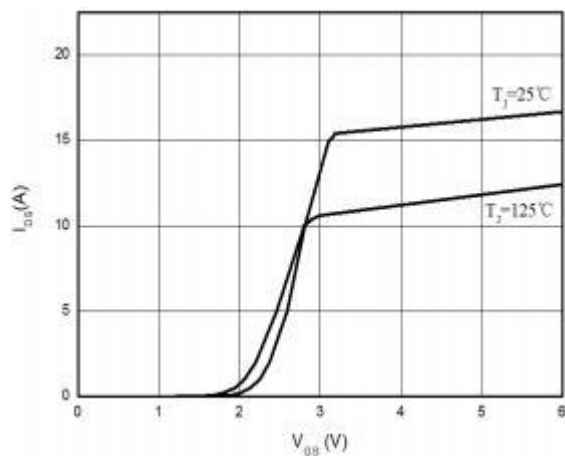


Figure 3. Typical Transfer Characteristics ($V_{DS}=5V$)

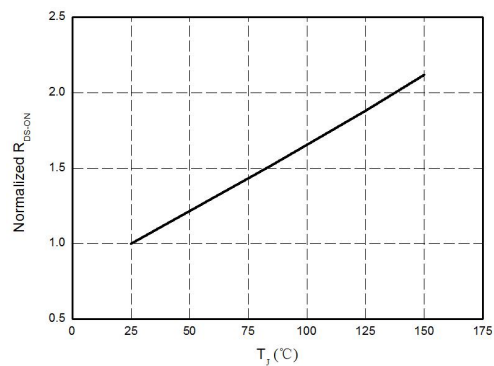


Figure 4. Normalized On-resistance

Typical Characteristics

$T_J=25^\circ\text{C}$ unless otherwise stated

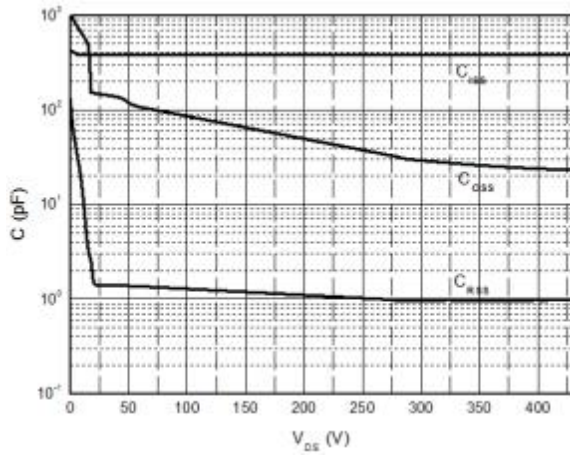


Figure 5. Typical Capacitance (f=1MHz)

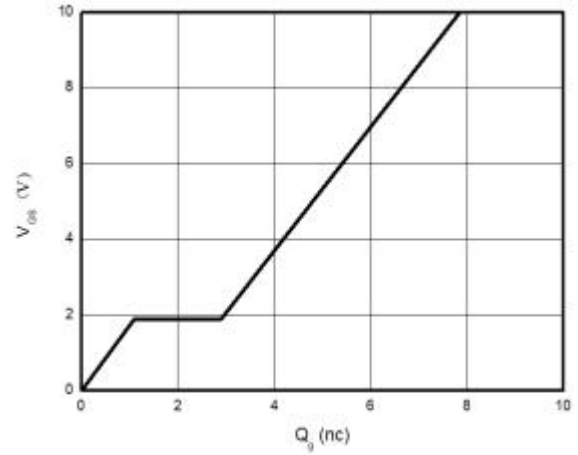


Figure 6. Typical Gate Charge ($V_{DS}=400\text{V}$, $I_D=1\text{A}$)

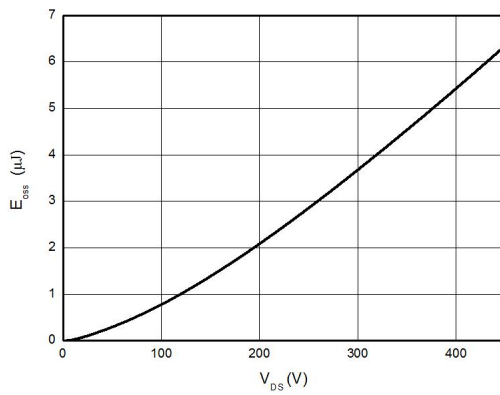


Figure 7. Typical C_{oss} Stored Energy

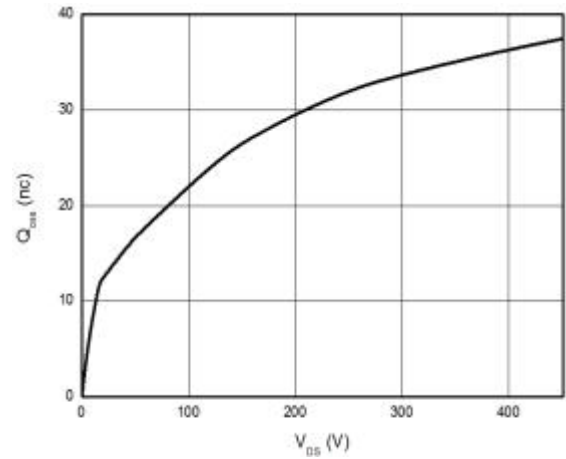


Figure 8. Typical Q_{oss}

Typical Characteristics

$T_J = 25^\circ\text{C}$ unless otherwise stated

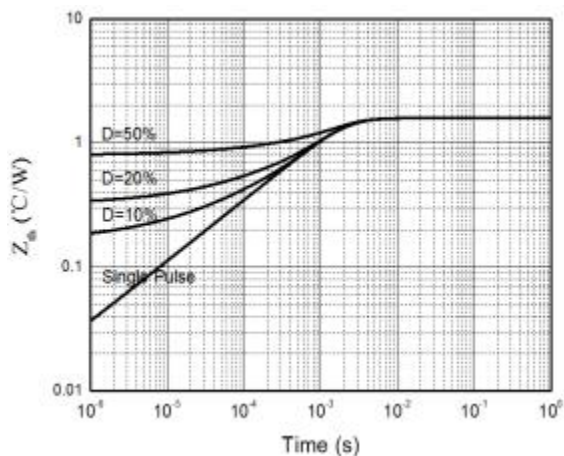


Figure 9. Transient Thermal Resistance

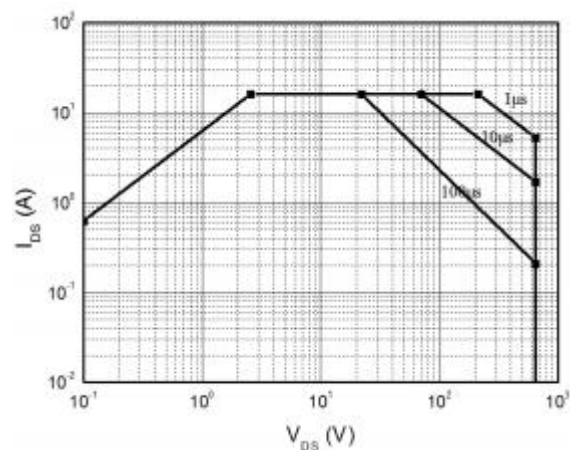


Figure 10. Safe Operating Area $T_J = 25^\circ\text{C}$

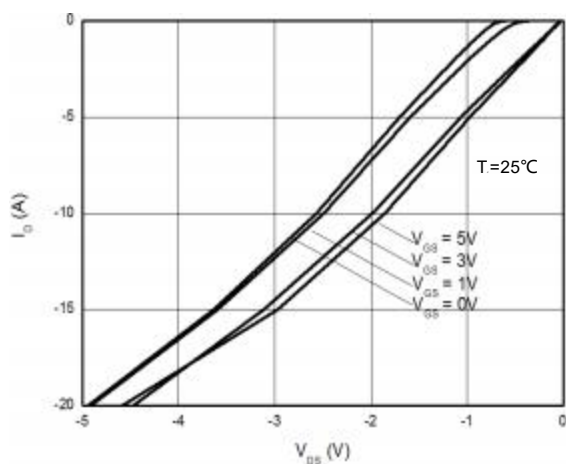


Figure 11. Channel Reverse Characteristics $T_J = 25^\circ\text{C}$

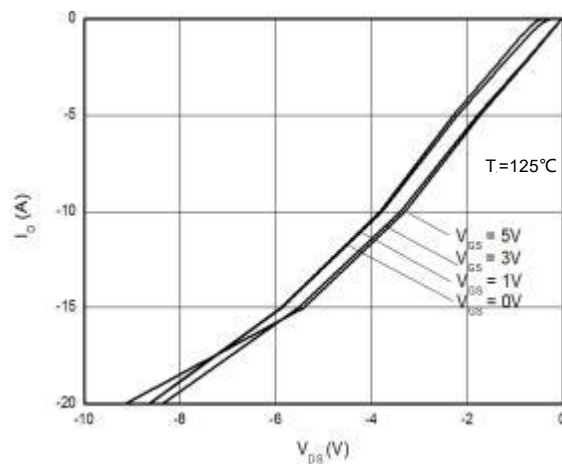
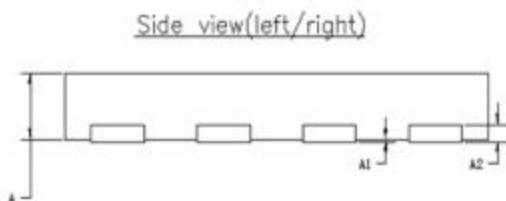
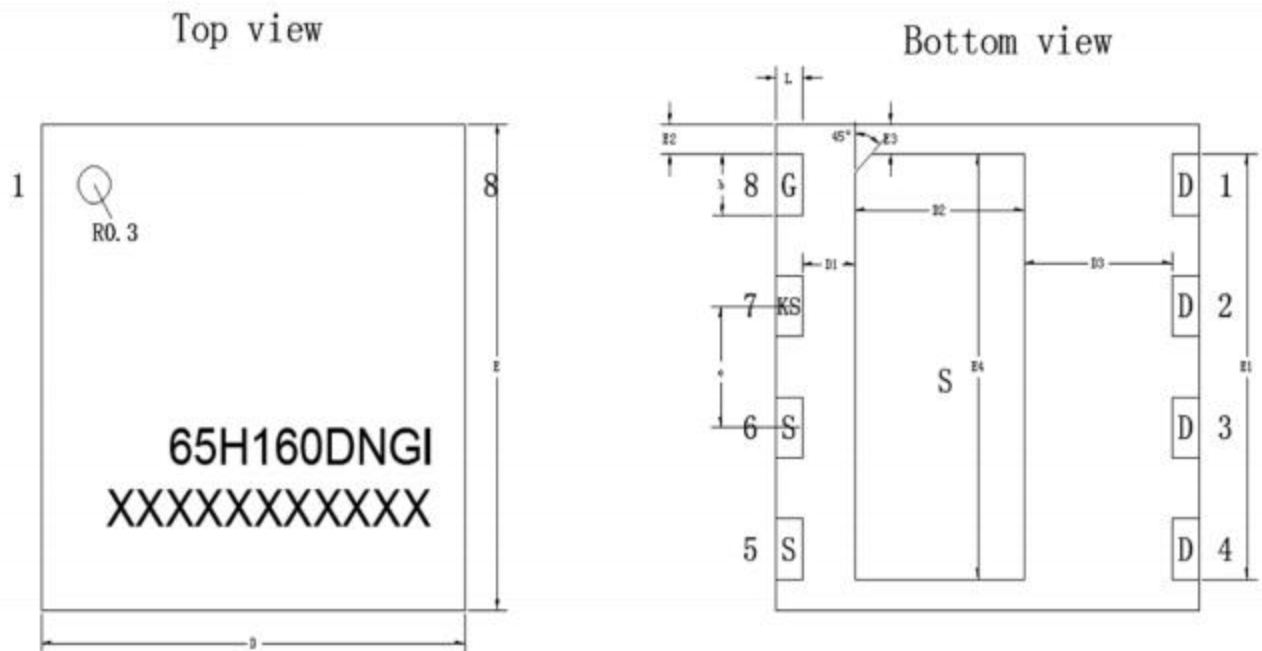


Figure 12 Channel Reverse Characteristics $T_J = 125^\circ\text{C}$

PACKAGE DIMENSIONS

DFN8x8-8L-1.10-A



Symbol	Min. (mm)	Mean. (mm)	Max. (mm)
A	1.05	1.10	1.15
A1	0	0.02	0.05
A2	0.203REF		
D	7.9	8	8.1
E	7.9	8	8.1
D1	0.9	1	1.1
D2	3.1	3.2	3.3
D3	2.7	2.8	2.9
E1	6.9	7	7.1
E2	0.4	0.5	0.6
E3	0.4	0.5	0.6
E4	6.9	7	7.1
e	1.9	2	2.1
b	0.9	1	1.1
L	0.4	0.5	0.6